M6000 PLUS

OLED Lifetime Test System

All Optimized for Multi-channel Power Driving Lighting and Measurement of OLED Lifetime

M6000 PLUS OLED Lifetime Test System is used to test the capability of OLED materials to withstand the continuous electrical source or environmental changes between high/low temperature, and therefore understands the chemical changes or physical damages caused by degradation in the designated time. It is applicable to OLED unit cell, module, panel. The lifetime test result can be used as a reference or basis for OLED material improvement and better quality.

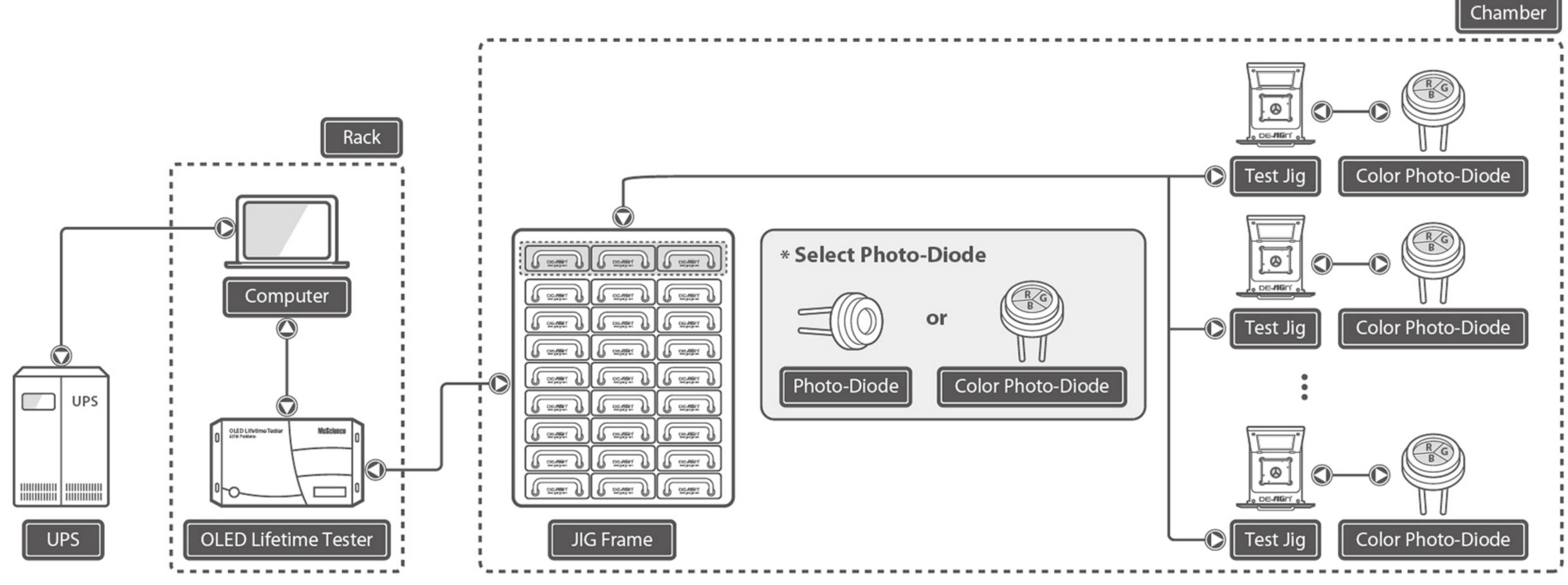


Relative/Absolute Lifetime Test
Relative/Absolute I-V-L Test
Aging Test
Multi Current/Photocurrent Range
Sequence Operation with mutiple Recipe
Acceleration Test using Thermal Chamber











System Components





System Specification

| Product Name | | M6000 PLUS OLED Lifetime Test System |
|------------------|-----------------|---|
| Function | | Lifetime Test, Aging Test, IV Scan during Lifetime Test |
| Capacity | | 32ch / Unit |
| Output Mode | | CV, CC, CL, PV, PC, PCV |
| Voltage | Range | ±20V |
| | Accuracy | ±0.05% + 10mV (F.S.R.) |
| Current | Range | [Range 1] ±1mA / [Range 2] ±10mA (Auto 2-Range Shunt Type) |
| | Accuracy | [Range 1] ±0.05% + 1uA (F.S.R.) / [Range 2] ±0.05% + 10uA (F.S.R.) |
| Photocurrent | Range | [Range 1] 0uA~10uA / [Range 2] 0uA~100uA / [Range 3] 0uA~1mA (Auto) |
| | Accuracy | [Range 1] ±0.05% + 5nA (F.S.R.) / [Range 2] ±0.05% + 10nA (F.S.R.) / [Range 3] ±0.05% + 50nA (F.S.R.) |
| Pulse | Frequency Range | 10 ~ 256Hz / 1Hz Step |
| | Duty | 1 ~ 99% / 1% Step |
| Measurement Item | | Time, Voltage, Current, Photo-Current, Luminance, CIE |
| Data Backup | | Automatic Data Backup in HW Memory in case of SW Disconnection |
| Interface | | LAN |

